

## **Scanning Electrochemical Potential Microscope**

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SEPM makes use of the potential gradient present in the electrical double layer formed at the interface of different phases, particularly liquid/solid interfaces. It allows mapping potential distribution across an electrode surface with atomic resolution, and also allows imaging surface topography as an ECSTM does. Potential profiling across the double layer opens new insights to electrochemical fundamentals; and larger range of tip-sample separation makes it possible to see poorly conducting materials, a feature that is advantageous over STM.